

Description

The AP16P01BF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

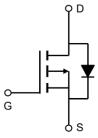
 $V_{DS} = -18V I_{D} = -16A$

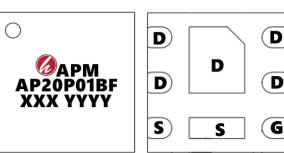
 $R_{DS(ON)} < 24m\Omega @ V_{GS}=10V$ (Type: $18m\Omega$)

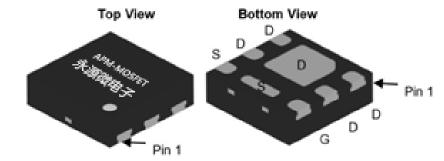
 $R_{DS(ON)} < 32m\Omega$ @ V_{GS} =4.5V (Type: 24 $m\Omega$)

Application

Electronic cigarette Load switch







Package Marking and Ordering Information

<u> </u>	<u> </u>		
Product ID	Pack	Marking	Qty(PCS)
AP16P01BF	DFN2*2-6L	AP16P01BF XXX YYYY	3000

Absolute Maximum Ratings (T_C=25°Cunless otherwise noted)

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Symbol	Parameter	Rating	Units
VDSS	Drain-Source Voltage	-18	V
VGSS	Gate-Source Voltage	±12	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	-16	А
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V¹	-8.6	А
IDM	Pulsed Drain Current note1	-30	А
P _D @T _C =25°C	Power Dissipation	1.6	W
RθJA	Thermal Resistance, Junction to Ambient	125	°C/W
TJ, TSTG	Operating and Storage Temperature Range	-55 to +150	°C



Electrical Characteristics (T_J=25℃, unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D = -250μA	-12	-18	-	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} = -20V, V _{GS} =0V,	-	-	-1	μΑ
IGSS	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±12V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D = -250μA	-0.4	-0.7	-1.0	V
RDS(on)	Static Drain-Source on-Resistance note2	V _{GS} = -10V, I _D = -4.1A		18	24	mΩ
RDS(on)	Static Drain-Source on-Resistance note2	V _{GS} = -4.5V, I _D = -4.1A	-	24	32	mΩ
RDS(on)	Static Drain-Source on-Resistance note2	V _{GS} = -2.5V, I _D = -3A	-	33	42	mΩ
Ciss	Input Capacitance		-	830	-	pF
Coss	Output Capacitance	V_{DS} = -10V, V_{GS} =0V, f=1.0MHz	-	132	-	pF
Crss	Reverse Transfer Capacitance		-	85	-	pF
Qg	Total Gate Charge		-	8.8	-	nC
Qgs	Gate-Source Charge	V _{DS} = -10V, I _D = -2A, V _{GS} = -4.5V	-	1.4	-	nC
Qgd	Gate-Drain("Miller") Charge		-	1.9	-	nC
td(on)	Turn-on Delay Time		-	10	-	ns
tr	Turn-on Rise Time	V _{DD} = -10V, I _D = -3.3A,	-	32	-	ns
td(off)	Turn-off Delay Time	R _G = 1Ω, V _{GEN} = -4.5V	-	50	-	ns
t _f	Turn-off Fall Time		-	51	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	-4.1	Α
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-16	Α
VSD	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S = -4.1A	-	-	-1.2	V

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width $\, \leqq \, 300 \text{us}$, duty cycle $\, \leqq \, 2\%$
- 3. The power dissipation is limited by 150 $^\circ\!\mathrm{C}$ junction temperature
- 4. The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.



Typical Characteristics

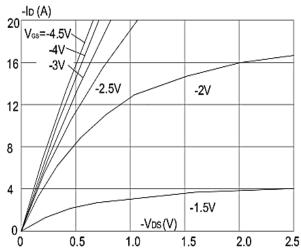


Figure1: Output Characteristics

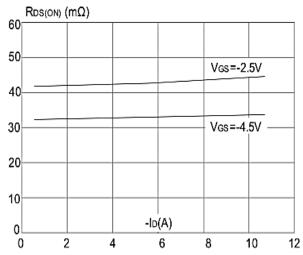


Figure 3:On-resistance vs. Drain Current

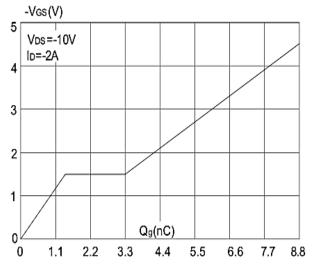


Figure 5: Gate Charge Characteristics

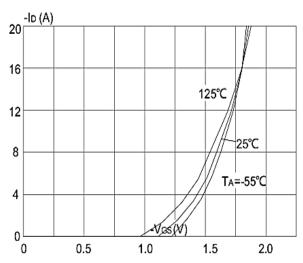


Figure 2: Typical Transfer Characteristics

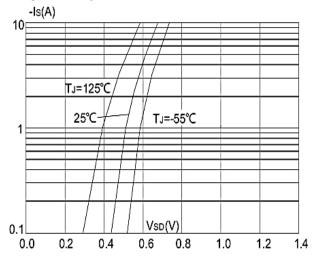


Figure 4: Body Diode Characteristics

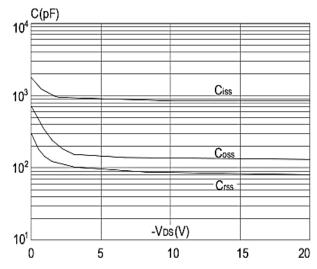


Figure 6: Capacitance Characteristics





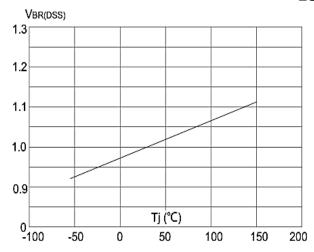


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

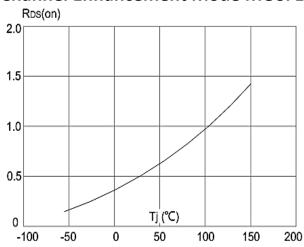


Figure 8: Normalized on Resistance vs.

Junction Temperature

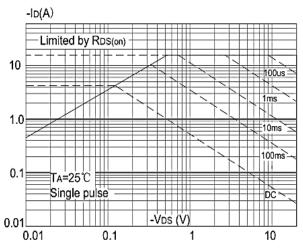


Figure 9: Maximum Safe Operating Area

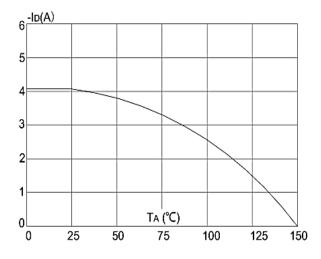


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

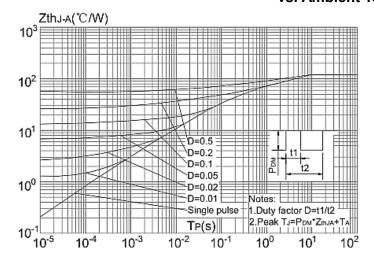
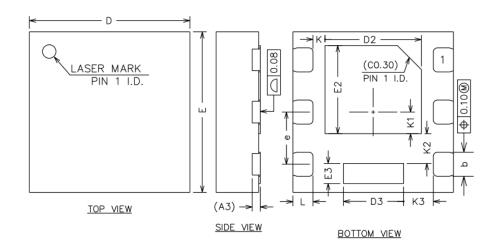


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient



Package Mechanical Data: QFN2*2-6L



Compleal			
Symbol	Min	Nom	Max
Α	0.50		0.54
A1	0.00	0.02	0.05
A3		0.10REF	
b	0.25	0.30	0.35
D	1.90	2.00	2.10
E	1.90	2.00	2.10
D2	1.10	1.20	1.30
E2	1.00	1.10	1.20
D3	0.65	0.75	0.85
E3	0.15	0.25	0.35
е	0.55	0.65	0.75
K	0.05		
K1	0.17		
K2	0.27		
K3	0.28		
L	0.20	0.25	0.30



-18V P-Channel Enhancement Mode MOSFET Attention

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AP16P01BF

-18V P-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve1.0	2020/9/8	Initial release

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